

Description

The XPX40NN10RD uses advanced technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 100V I_{D} = 40A$

 $R_{DS(ON)}$ < 14m Ω @ V_{GS} =10V

Application

Consumer electronic power supply

Motor control

Synchronous-rectification

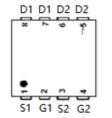
Isolated DC

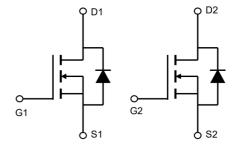
Marking and pin assignment



DFN5X6双基

Schematic Diagram





Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX40NN10RD	PDFN5*6-8L	XPX40NN10RD XXX YYYY	5000

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain source voltage	100	V
VGS	Gate source voltage	±20	V
ID	Continuous drain current¹¹, Tc=25 ℃	40	А
ID, pulse	Pulsed drain current ²⁾ , Tc=25 ℃	120	А
P _D	Power dissipation ³⁾ , Tc=25 [°] C	71	W
EAS	Single pulsed avalanche energy ⁵⁾	57	mJ
Tstg, Tj	Operation and storage temperature	-55 to 150	$^{\circ}$ C
RθJC	Thermal resistance, junction-case	1.76	°C/W
RθJA	Thermal resistance, junction-ambient ⁴⁾	25	°C/W



Electrical Characteristics (T_C=25°Cunless otherwise noted)

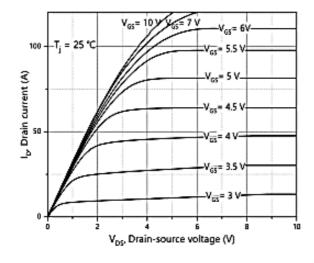
Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
BVDSS	Drain-source breakdown voltage	V _{GS} =0 V, I _D =250 μA	100	107		V
VGS(th)	Gate threshold voltage	V_{DS} = V_{GS} , I_{D} =250 μA	1.2	1.5	2.5	V
RDS(ON)	Drain-source on-state resistance	V _{GS} =10 V, I _D =10 A		14	20	mΩ
RDS(ON)	Drain-source on-state resistance	V _{GS} =4.5 V, I _D =7 A		18	25	mΩ
IGSS	Gate-source leakage current	V _{GS} =±20 V			±100	nA
IDSS	Drain-source leakage current	V_{DS} =100 V, V_{GS} =0 V			1	uA
Ciss	Input capacitance	V _{GS} =0 V,		1013.9		pF
Coss	Output capacitance	V _{DS} =50 V,		185.4		pF
Crss	Reverse transfer capacitance	<i>f</i> =100 kHz		9.8		pF
td(on)	Turn-on delay time			16.6		ns
t _r	Rise time	V_{GS} =10 V, V_{DS} =50 V, R_{G} =10 Ω , I_{D} =5 A		3.8		ns
td(off)	Turn-off delay time			75.5		ns
t _f	Fall time	1 <u>0</u> -071		46		ns
Qg	Total gate charge			16.2		nc
Qgs	Gate-source charge	$I_D=5 A$, $V_{DS}=50V$,		2.8		nc
Qgd	Gate-drain charge	V _{DS} -50V, V _{GS} =10V		4.1		nc
Vplateau	Gate plateau voltage			3		V
ls	Diode forward current	\(\(CC\\)\(\(L\)\)		30		Α
ISP	Pulsed source current	VGS <vth< td=""><td></td><td>90</td><td></td><td>Α</td></vth<>		90		Α
trr	Reverse recovery time		49			ns
Qrr	Reverse recovery charge	I _S =1A, di/dt=100 A/μs	61.8			nc
Irrm	Peak reverse recovery current		2.4			Α

Note:

- 1. Calculated continuous current based on maximum allowable junction temperature.
- 2. Repetitive rating; pulse width limited by max. junction temperature.
- 3. Pd is based on max. junction temperature, using junction-case thermal resistance.
- 4. The value of R_{Θja} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_a=25 °C.
- 5 、 $V_{DD}{=}50$ V, $R_{G}{=}25$ $\Omega,$ $L{=}0.3$ mH, starting $T_{j}{=}25$ °C.



Typical Characteristics



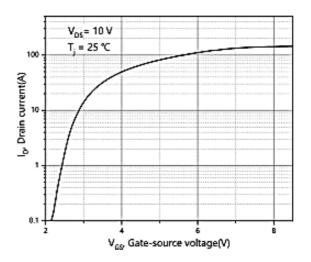
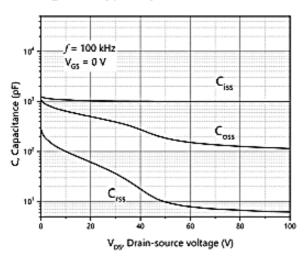


Figure 1, Typ. output characteristics





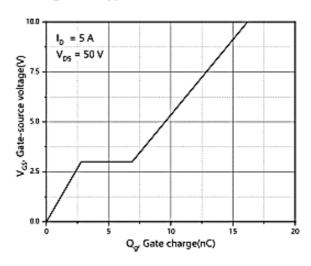
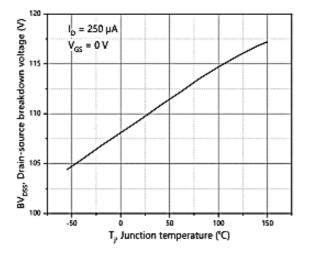


Figure 3, Typ. capacitances

Figure 4, Typ. gate charge



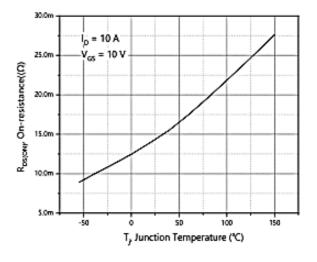
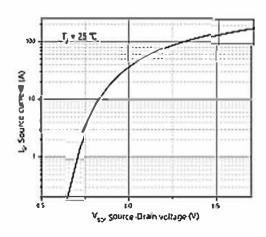


Figure 5, Drain-source breakdown voltage

Figure 6, Drain-source on-state resistance





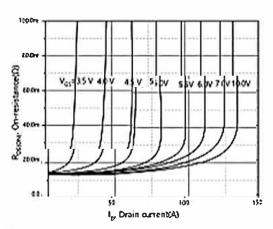
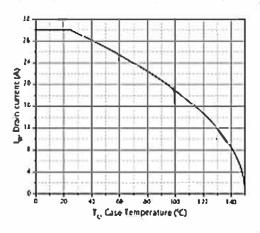


Figure 7. Forward characteristic of body diode

Figure 8. Drain-source on-state resistance



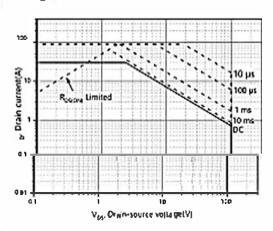
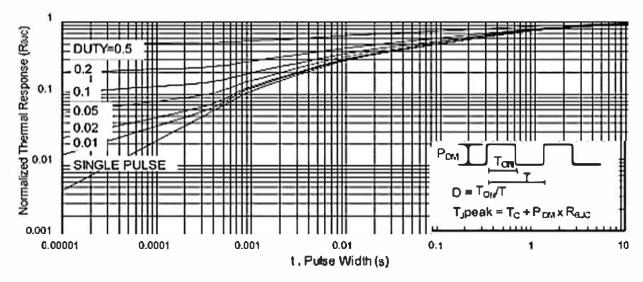


Figure 9, Drain current

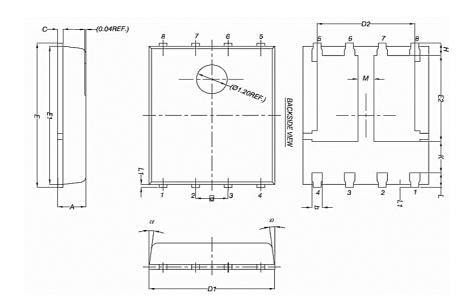
Figure 10, Safe operation area Tc=25 °C



Figu11. Normalized Maximum Transient Thormal Impedance



Package Mechanical Data-DFN5*6-8L-JQ Double



		Common	
Symbol	mm		
	Mim	Nom	Max
Α	0.90	1.00	1.10
b	0.33	0.41	0.51
С	0.20	0.25	0.30
D1	4.80	4.90	5.00
D2	3.61	3.81	3.96
E	5.90	6.00	6.10
E1	5.70	3.30	3.45
E2	3.38	3.05	3.20
e		1.27BSC	
Н	0.41	0.51	0.61
K	1.10		
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
M	0.50		
a	0°		12°



Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245℃±5℃	5sec±1sec
Pb-Free device	260℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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